

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/609,499	LEE ET AL.	
Examiner	Art Unit	
Nathan W. Ha	2814	

SEARCHED					
Class	Subclass	Date	Examiner		
257	734- 739	2/28/21	14		
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INTERFERENCE SEARCHED					
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SEARCH NOTES (INCLUDING SEARCH STRATEGY)				
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